

Thin manganese films on Si(111)-(7 × 7): Electronic structure and strain in suicide formation

Kumar A, Tallarida M, Hansmann M, Starke U, Horn K.
Journal of Physics D: Applied Physics
2004; 37(7):1083-1090

ARTICLE IDENTIFIERS

DOI: 10.1088/0022-3727/37/7/021

PMID: unavailable

PMCID: not available

JOURNAL IDENTIFIERS

LCCN: not available

pISSN: 0022-3727

eISSN: not available

OCLC ID: not available

CONS ID: not available

US National Library of Medicine ID: not available

This article was identified from a query of the SafetyLit database.